



# ***ORIENT DISPLAY***

**MAKE THINGS POSSIBLE**

**SPECIFICATION  
FOR  
IoT MODULE  
MODULE NO: AMV-3568A0  
REVISION NO: 0**

Customer's Approval:

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	SIGNATURE	DATE
PREPARED BY (RD ENGINEER)		
CHECKED BY		
APPROVED BY		



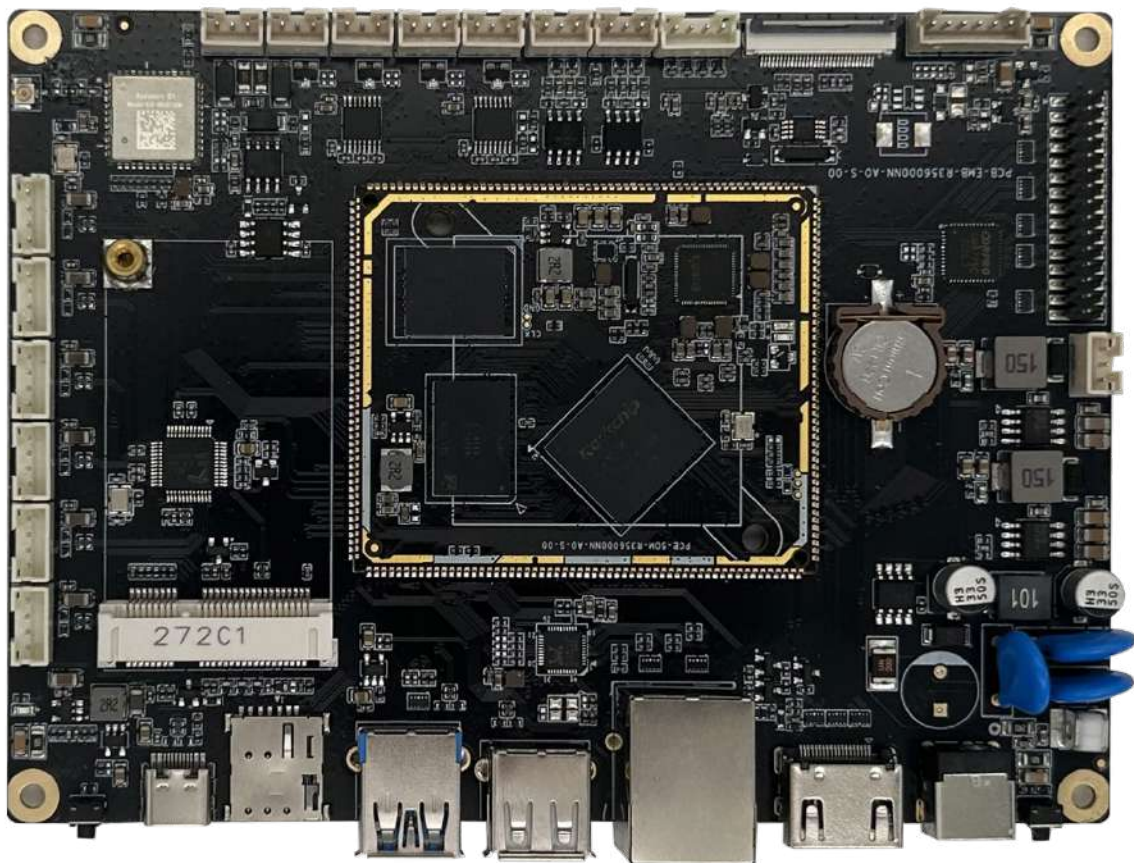
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# 1.MODULE DESCRIPTION

**AMV-3568A0** motherboard is a high-performance embedded motherboard that is equipped with the Rockchip RK3566, the latest generation of low-cost, high-performance multi-core processor. It also has 2GB of memory and 16GB of eMMC storage, and can run operating systems such as Android 11 and Linux.

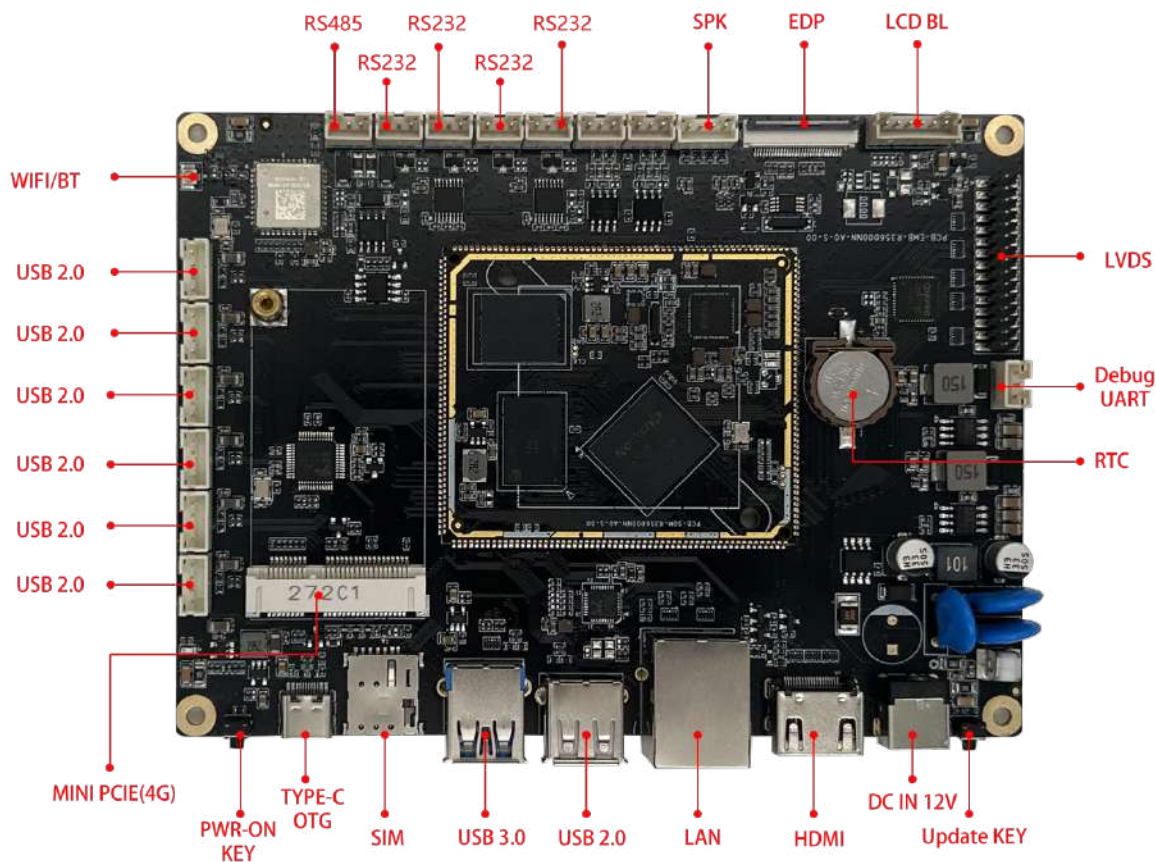
It provides a rich range of peripheral interfaces, allowing for flexible connection to a large number of external devices such as barcode scanners, cameras, barcode printers, and card readers. The high-spec video engine, combined with H.265 hardware decoding and 2K video resolution, provides ultra-high-definition video output. The multi-format display interface makes it flexible for use in various industry scenarios such as smart retail, face access control, and financial self-service terminals.



## 2.GENERAL INFORMATION

Product Introduce	
Operating System	Linux/Android
CPU	RK3566 ARM quad-core ARM Cortex-A55, Highest frequency is 1.8GHz
Memory	2GB LPDDR4+16GB EMMC(RAM, ROM size can be selected)
USB TYPE-C	OTG
Display interface	HDMI*1、LVDS*1、EDP*1
Ethernet	LAN*1
I/O interface	USB3.0 TYPE-A*1、USB2.0 TYPE-A*1、DB UART*1、SPK*1、 RS232*4、RS485*1、WIFI/BT*1、USB2.0**6、MINI PCIE(4G)*1、 TF card*1
Power Supply	DC-in
	Typ. 12V
Power Consumption	2.5W(Static desktop with default brightness)
System upgrade	Support local USB upgrade
System Language	Multilingualism
Mechanical	107.00*146.00mm
Weight	103g

### 3.INTERFACE DESCRIPTION



No.	Item	Symbol
1	DC	Power DC 12V
2	HDMI	HDMI 2.0
3	USB	USB2.0*1、USB3.0*1、TYPE-C OTG*1
4	LAN	LAN*1 10/100/1000M
5	SIM CARD	4G LTE
6	TF CARD	TF card slot

#### Debug UART:

Pin No.	Symbol	Pin No.	Symbol
1	DEBUG_TX(3.3V)	3	GND
2	DEBUG_RX(3.3V)	/	/

**LVDS:**

Pin No.	Symbol	Pin No.	Symbol
1	VDD	16	LVDS_CLK1P
2	VDD	17	LVDS_D3N
3	VDD	18	LVDS_D3P
4	GND	19	LVDS_D4N
5	GND	20	LVDS_D4P
6	GND	21	LVDS_D5N
7	LVDS_D0N	22	LVDS_D5P
8	LVDS_D0P	23	LVDS_D6N
9	LVDS_D1N	24	LVDS_D6P
10	LVDS_D1P	25	GND
11	LVDS_D2N	26	GND
12	LVDS_D2P	27	LVDS_CLK2N
13	GND	28	LVDS_CLK2P
14	GND	29	LVDS_D7N
15	LVDS_CLK1N	30	LVDS_D7P

**LCD\_BL:**

Pin No.	Symbol	Pin No.	Symbol
1	VCC_BL	4	EN
2	VCC_BL	5	GND
3	PWM	6	GND

**EDP:**

Pin No.	Symbol	Pin No.	Symbol
1	NC	16	GND
2	GND	17	HPD
3	D1N	18	BL_GND
4	D1P	19	BL_GND
5	GND	20	BL_GND
6	D0N	21	BL_GND

7	D0P	22	BL_EN
8	GND	23	BL_PWM
9	CLKP/AUXP	24	NC
10	CLKN/AUXN	25	NC
11	GND	26	BL_PWR
12	LCD_VCC	27	BL_PWR
13	LCD_VCC	28	BL_PWR
14	NC	29	BL_PWR
15	GND	30	NC

**SPK:**

Pin No.	Symbol	Pin No.	Symbol
1	OUTPR	3	OUTNL
2	OUTNR	4	OUTPL

**RS232\*4:**

Pin No.	Symbol	Pin No.	Symbol
1	RS232_RX	3	GND
2	RS232_TX	/	/

**RS485:**

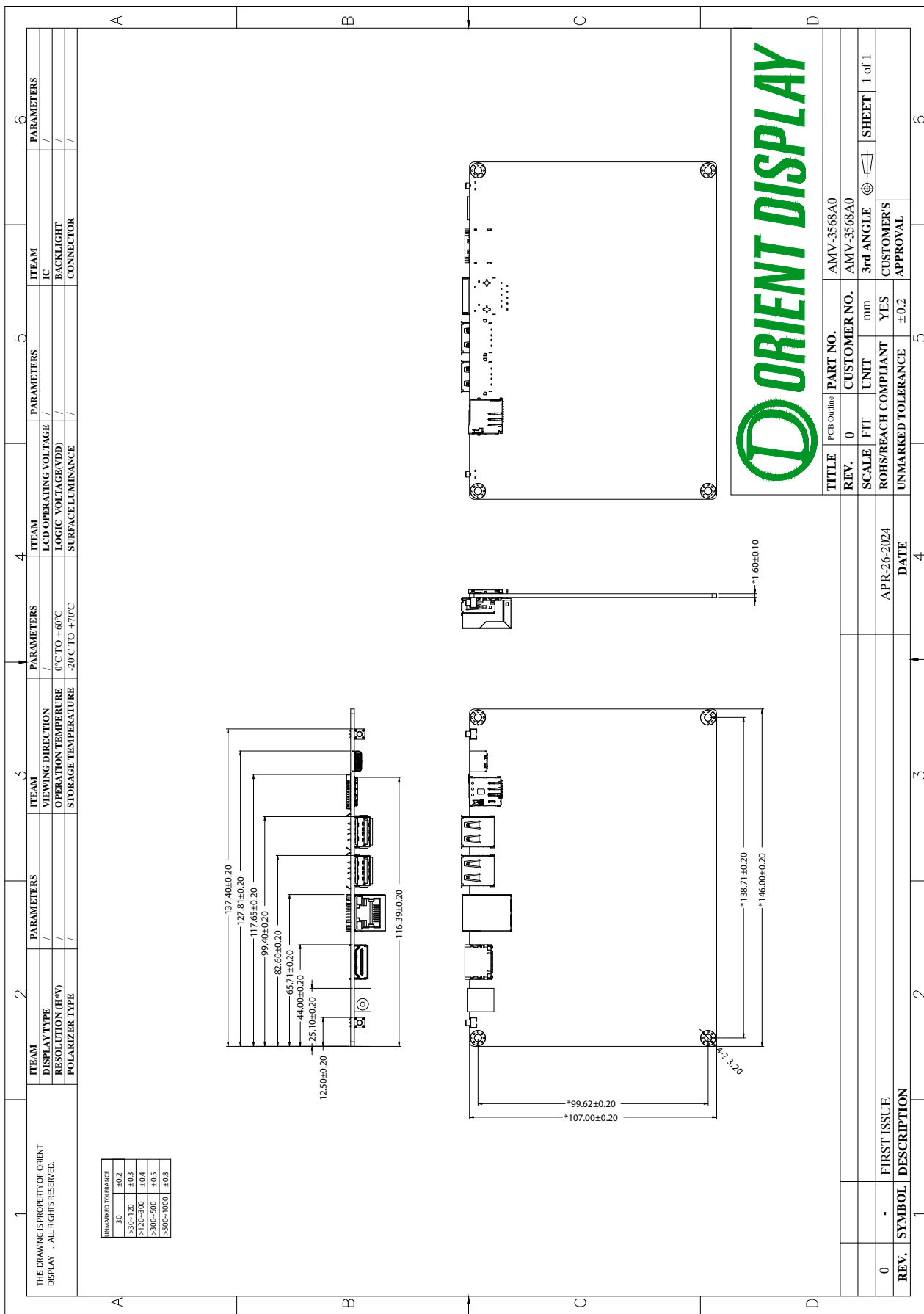
Pin No.	Symbol	Pin No.	Symbol
1	RS485_A	3	GND
2	RS485_B	/	/

**USB2.0\*6:**

Pin No.	Symbol	Pin No.	Symbol
1	GND	3	DM
2	DP	4	VCC_USB



# 4. MOUDLE EXTERNAL DIMENSIONS



## 5.ENVIRONMENTAL CONDITIONS

Item	Symbol	Min.	Max.	Unit
Operation Temperature	Top	0	+60	°C
Storage Temperature	Tst	-20	+70	°C
Humidity	RH	-	90%	%RH

## 6.RELIABILITY TEST CONDITIONS

No.	Test Item	Test condition		Inspection after test
1	High Temperature Storage Test	+70°C/72 hours		Inspection after 2~4 hours storage at room temperature, the sample shall be free from defects : 1.Current changing value before test and after test is 50% larger. 2. Function defect : Non-display, abnormal-display 3.Visual defect : Glass crack.
2	Low Temperature Storage Test	-20°C/72 hours		
3	High Temperature Operating Test	+60°C/48 hours		
4	Low Temperature Operating Test	0°C/48 hours		
5	Temperature Cycle Storage Test	-20°C ~ 25°C ~ +70°C/10 cycles (30 min.) (10 min.) (30 min.)		
6	High Temperature High Humidity Test	+50°C*90% RH/48 hours		
7	Vibration Test	Frequency : 250 r/min Amplitude : 1 inch Time: 45 min		
8	Drop Test	Drop direction: 1 corner/3 edges/6 sides ,10 times		
		Packing weight(kg)	Drop height(cm)	
		<11	80±1.6	
		11≤G<21	60±1.2	
		21≤G<31	50±1.0	
31≤G<40	40±0.8			
9	ESD Test	Air discharge: ±8 KV, 10 times Contact discharge: ±4 KV, 10 times		

Remark :

- 1.The tested samples should be applied to only one test item.
- 2.Sample size for each test item is 3~5 pcs.
- 3.For High temperature high humidity test, Pure water(Resistance>10MΩ) should be used.
- 4.In case of malfunction defect caused by ESD damage, if it would be recovered to normal state after resetting, it would be judged as a good part.
- 5.Failure judgement criterion: Basic specification, Electrical characteristic, Mechanical characteristic, Optical characteristic.

## 7.REMARK:

- Avoid any inappropriate external force or strong vibration in the assembly process.
- High temperature, high humidity or rapid temperature changes may affect performance. Store and use the product in an appropriate environment.
- Avoid dust, oil mist, acid, alkali and chloride damage to the product.
- Wear wrist straps, antistatic gloves and clothes during assembly to prevent electrostatic discharge (ESD).
- When assembling, use ionic fan to prevent electrostatic discharge (ESD).
- Follow the correct time sequence when operating.
- Turn off the power when connecting or disconnecting the circuit.
- Ensure that the shell is connected to the ground (PE) in the operating environment.